



The Materials Metrology™ Company

Press Release

ReVera Announces Purchase of the VeraFlex™ Metrology System by Toshiba

Expanded deployment of comprehensive materials metrology capabilities
enables faster development and higher production yield

Sunnyvale, Calif., December 6, 2006 – ReVera Incorporated, the materials metrology company, today announced an additional purchase of its VeraFlex™ metrology system by Toshiba Corporation, a leader in the development and manufacture of electronic devices and components. Toshiba will apply the broad measurement capabilities of this additional VeraFlex system to their development and manufacturing activities. The deployment of multiple VeraFlex systems will enable both rapid implementation of critical new multilayer dielectric films and enhanced production through advanced metrology control.

“The production of Toshiba’s most advanced devices utilizes a variety of new materials and advanced manufacturing techniques,” commented ReVera CEO Dave Ring. “However, they determined that the level of control required for these processes was beyond the capabilities of traditional optical metrology. To address the increased requirements, Toshiba selected VeraFlex. VeraFlex provides the critical capabilities and reliable performance they need to speed development and ramp, and then effectively monitor their volume production. We are pleased by Toshiba’s selection and are committed to playing an increasing role in supporting the IC manufacturing market with comprehensive materials metrology solutions.”

About VeraFlex

The VeraFlex system addresses the increasing demands for materials metrology from development through production on product and monitor wafers. Based on XPS, an industry standard for materials characterization, it offers broad measurement capabilities – including thickness, composition, profile, bonding states, interface quality and surface condition – in a production-proven system. This provides a flexible solution for a wide range of emerging materials metrology requirements for 65 nm, 45 nm and beyond.

About ReVera

ReVera Incorporated is a leading provider of materials metrology solutions for advanced semiconductor processing. Its products allow device manufacturers to measure, monitor and control critical materials properties, enabling them to rapidly integrate and manage the new materials required for 65 nm, 45 nm and beyond. ReVera systems are proven in production in a broad range of applications, and are backed by a global network of applications, field service, sales and logistics personnel. ReVera was established in 2004 as a management-led spin-out from Physical Electronics and its wholly owned subsidiary, Charles Evans and Associates.